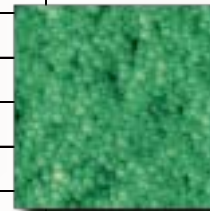




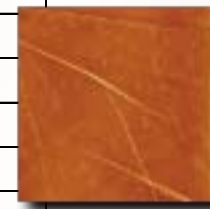
原子力顯微鏡 MS-818 AFM

規格配備

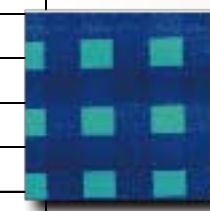
Probe-deflection detection method	Optical lever technique
Operation mode	DC mode / AC mode / Non-contact mode MFM (optional) / EFM (optional) / SThM (optional)
Amplitude/Phase imaging	YES
Line/Frame scan	YES
Automatic probe approach	YES
Continuous scan	YES
Force curve chart	YES
Constant force scan	YES
Constant height scan	YES
Scan rotation	0 ~ 360°
Image pixel	64 ~ 1024, independent length/width
Image export	bmp file
Raw data export	txt file (for Matlab, Excel, Gwyddion and WSxM)
Scanner	
Scanning range (X/Y/Z)	15 μm × 15 μm × 5 μm (other range on request)
Open-loop resolution (X/Y/Z)	0.23 nm
Closed-loop resolution (X/Y/Z)	30 nm
Sample stage	
Size	Diameter 50mm × thickness 10mm
Maximum load	100g (static)
XY sample positioning	10mm × 10mm
Image analysis	
Real-time line flatten	YES
Post-scan frame flatten	YES
Line profile measurement	YES
Roughness measurement	YES
Contrast/brightness adjustment	YES
Multiple color palettes	YES
3D image	YES
Line average	YES
Electronics	



- Sample type: PS sphere clustered on graphite surface.
- Scan mode: AC mode
- Size: 4μm x 4μm



- Sample type: Carbon nanotubes (CNT) on silicon substrate.
- Scan mode: AC mode
- Size: 10μm x 10μm



- Sample type: Calibration sample, array of silicon square islands.
- Scan mode: AC mode
- Size: 8μm x 8μm



原子力顯微鏡 MS-818 AFM

規格配備

Electronics	
AD/DA resolution	16-bit
Scan rate	0.1 ~ 3 Hz
Feedback control platform	Real-time FPGA
Embedded Lock-in amplifier	FPGA based, 1k ~ 1M Hz
Simultaneous imaging channels	4
User input channel	1 (-10V ~ +10V)
Independent laser switch	YES
Power rating	100 ~ 240VAC / 50~60 Hz / 180W
Misc.	
PC operation system	Windows 2000/ XP/ Vista / 7
Program development platform	NI LabVIEW
PC interface	Ethernet
Targeting optical microscope	optional



- Sample type: PS sphere clustered on graphite surface.
- Scan mode: AC mode
- Size: 4µm x 4µm



- Sample type: Carbon nanotubes (CNT) on silicon substrate.
- Scan mode: AC mode
- Size: 10µm x 10µm



- Sample type: Calibration sample, array of silicon square islands.
- Scan mode: AC mode
- Size: 8µm x 8µm